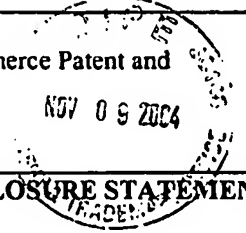


FORM PTO-1449 U.S. Department of Commerce Patent and Trademark Office 	Docket No. INTEL1120 (P15611)	Serial No.: 10/748,389
	Applicant(s): Yamakawa, et al.	
INFORMATION DISCLOSURE STATEMENT BY APPLICANT	Filing Date: December 29, 2003	Group Art Unit: 2857

U.S. PATENT DOCUMENTS

EXAM. INITIALS		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB- CLASS	FILING DATE
/K.W./	A	6,514,767	2/4/03	Michael Natan	436	166	

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EXAM. INITIALS		DOCUMENT NUMBER	DATE	COUNTRY	CLASS	SUB- CLASS	TRANSLATION (YES/NO)

OTHER DOCUMENTS (Including Author, Title, Date, Pertinent Pages)

/K.W./	B	Doering, et al., "Spectroscopic Tags Using Dye-Embedded Nanoparticles and Surface-Enhanced Raman Scattering", <i>Analytical Chemistry</i> , :5-9
/K.W./	C	Fuh, et al., "Analytical SPLITT Fractionation: Rapid Particle Size Analysis and Measurement of Oversized Particles", <i>Anal Chem. Soc.</i> 64:3125-3132 (1992)
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/K.W./	E	Mulvaney, et al., "Glass-Coated, Analyte-Tagged Nanoparticles: A New Tagging System Based on Detection with Surface-Enhanced Raman Scattering", <i>Am Chem Soc.</i> 19:4784-4790 (2003).

EXAMINER GT6421411.1 /P. Kathryn Wright/ (05/03/2007) 1090132-5	DATE CONSIDERED
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EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.